**Entrope™ High-Frequency Noise Probe System**

**Entrope™ Probe** (patented)  
Example: n-MOSFET (Lg: 120 nm)

### Specification

<table>
<thead>
<tr>
<th>Probe type</th>
<th>Frequency</th>
<th>Floor noise (minimum)</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>Entrope™ 101A</strong></td>
<td>100k - 100MHz</td>
<td>~3×10⁻²³ (A²/Hz) @ 10 MHz</td>
</tr>
<tr>
<td><strong>Entrope™ 102A</strong></td>
<td>100k - 100MHz</td>
<td>~5×10⁻²³ (A²/Hz) @ 10 MHz</td>
</tr>
</tbody>
</table>

**Schematic block diagram**

**Entrope™ Noise Probe System** dramatically extends the frequency range of noise measurements compared to conventional low-frequency (1/f) noise measurement systems. The probe tips are configured to order to suit your DUTs.

- Thermal/shot noise evaluation
- RTN and 1/f noise measurements at high frequencies
- Measurement-based SPICE noise models and predictive circuit design

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